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- Operates With Single 5-V Power Supply
- LinBiCMOS<sup>™</sup> Process Technology
- Two Drivers and Two Receivers
- ±30-V Input Levels
- Low Supply Current . . . 8 mA Typical
- Meets or Exceeds TIA/EIA-232-F and ITU Recommendation V.28
- Designed to be Interchangeable With Maxim MAX232
- Applications TIA/EIA-232-F Battery-Powered Systems Terminals Modems Computers
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015
- Package Options Include Plastic Small-Outline (D, DW) Packages and Standard Plastic (N) DIPs

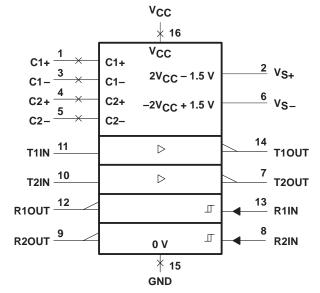
### description

The MAX232 device is a dual driver/receiver that includes a capacitive voltage generator to supply EIA-232 voltage levels from a single 5-V supply. Each receiver converts EIA-232 inputs to 5-V TTL/CMOS levels. These receivers have a typical threshold of 1.3 V and a typical hysteresis of 0.5 V, and can accept  $\pm$ 30-V inputs. Each driver converts TTL/CMOS input levels into EIA-232 levels. The driver, receiver, and voltage-generator functions are available as cells in the Texas Instruments LinASIC<sup>TM</sup> library.

The MAX232 is characterized for operation from  $0^{\circ}$ C to 70°C. The MAX232I is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.

D, DW, OR N PACKAGE (TOP VIEW)				
C1+ [	• 1	U <sub>16</sub>	]v <sub>cc</sub>	
V <sub>S+</sub> [	2	15	] GND	
C1-[	3	14		
C2+ [	4	13	R1IN	
C2- [	5	12	R10UT	
V <sub>S</sub> _[	6	11	] T1IN	
T2OUT	7	10	] T2IN	
R2IN [	8	9	R2OUT	

# logic symbol<sup>†</sup>



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

	PACKAGED DEVICES			
TA	SMALL OUTLINE (D)	SMALL OUTLINE (DW)	PLASTIC DIP (N)	
0°C to 70°C	MAX232D‡	MAX232DW <sup>‡</sup>	MAX232N	
-40°C to 85°C	MAX232ID <sup>‡</sup>	MAX232IDW <sup>‡</sup>	MAX232IN	

### AVAILABLE OPTIONS

<sup>‡</sup> This device is available taped and reeled by adding an R to the part number (i.e., MAX232DR).



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# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Input supply voltage range, V <sub>CC</sub> (see Note 1)	0.3 V to 6 V
Positive output supply voltage range, V <sub>S+</sub>	$\dots$ V <sub>CC</sub> – 0.3 V to 15 V
Negative output supply voltage range, V <sub>S</sub>	
Input voltage range, VI: Driver	0.3 V to V <sub>CC</sub> + 0.3 V
Receiver	±30 V
Output voltage range, V <sub>O</sub> : T1OUT, T2OUT	$V_{S-}$ – 0.3 V to $V_{S+}$ + 0.3 V
R1OUT, R2OUT	$\dots \dots \dots -0.3 \text{ V to V}_{CC} + 0.3 \text{ V}$
Short-circuit duration: T1OUT, T2OUT	Unlimited
Package thermal impedance, $\theta_{JA}$ (see Note 2): D package	113°C/W
DW package	105°C/W
N package	
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to network ground terminal.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

# recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>		4.5	5	5.5	V
High-level input voltage, VIH (T1IN,T2IN)		2			V
Low-level input voltage, VIL (T1IN, T2IN)				0.8	V
Receiver input voltage, R1IN, R2IN				±30	V
	MAX232	0		70	°C
Operating free-air temperature,T <sub>A</sub>	MAX232I	-40		85	



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### TYP<sup>†</sup> PARAMETER **TEST CONDITIONS** MIN MAX UNIT T1OUT, T2OUT $R_L = 3 k\Omega$ to GND 7 5 V Vон High-level output voltage $I_{OH} = -1 \text{ mA}$ R10UT, R20UT 3.5 T1OUT, T2OUT $R_I = 3 k\Omega$ to GND -7 -5 VOL Low-level output voltage<sup>‡</sup> V R10UT, R20UT 0.4 IOL = 3.2 mA Receiver positive-going input VIT+ R1IN, R2IN $V_{CC} = 5 V,$ T<sub>A</sub> = 25°C 1.7 2.4 V threshold voltage Receiver negative-going input R1IN, R2IN $V_{CC} = 5 V,$ V VIT- $T_A = 25^{\circ}C$ 0.8 1.2 threshold voltage R1IN, R2IN V<sub>hys</sub> Input hysteresis voltage $V_{CC} = 5 V$ 0.2 0.5 1 V 3 7 Receiver input resistance R1IN, R2IN VCC = 5, T<sub>A</sub> = 25°C 5 kΩ ri Output resistance T1OUT, T2OUT $V_{S+} = V_{S-} = 0,$ $V_0 = \pm 2 V$ 300 Ω r<sub>o</sub> $V_{O} = 0$ los§ Short-circuit output current T1OUT, T2OUT V<sub>CC</sub> = 5.5 V, ±10 mΑ Short-circuit input current T1IN, T2IN 200 $V_I = 0$ μΑ IIS V<sub>CC</sub> = 5.5 V, All outputs open, 8 10 ICC Supply current mΑ $T_A = 25^{\circ}C$

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature range (unless otherwise noted)

<sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

<sup>‡</sup> The algebraic convention, in which the least positive (most negative) value is designated minimum, is used in this data sheet for logic voltage levels only.

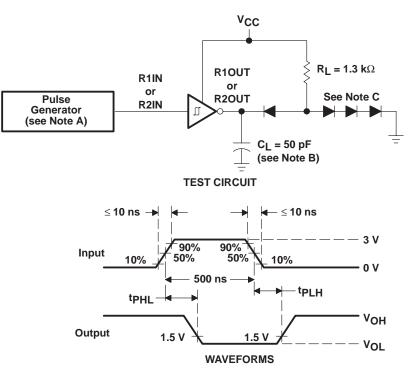
§ Not more than one output should be shorted at a time.

# switching characteristics, $V_{CC} = 5 V$ , $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	MIN T	YP MA	
<sup>t</sup> PLH(R)	Receiver propagation delay time, low- to high-level output	See Figure 1	Ę	500	ns
<sup>t</sup> PHL(R)	Receiver propagation delay time, high- to low-level output	See Figure 1	Ę	500	ns
SR	Driver slew rate	$R_L = 3 k\Omega$ to 7 k $\Omega$ , See Figure 2		3	) V/µs
SR(tr)	Driver transition region slew rate	See Figure 3		3	V/µs



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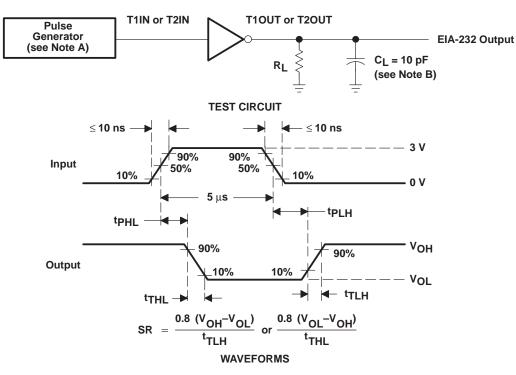
# PARAMETER MEASUREMENT INFORMATION

- NOTES: A. The pulse generator has the following characteristics:  $Z_0 = 50 \Omega$ , duty cycle  $\leq 50\%$ .
  - B. CL includes probe and jig capacitance.
  - C. All diodes are 1N3064 or equivalent.

Figure 1. Receiver Test Circuit and Waveforms for tPHL and tPLH Measurements



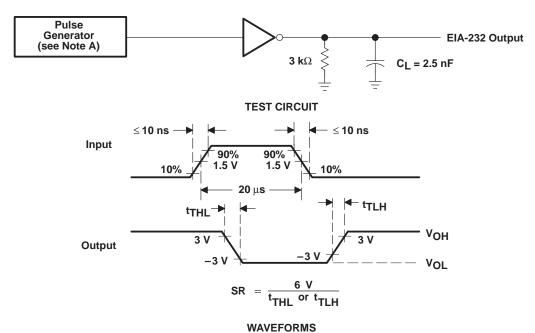
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# PARAMETER MEASUREMENT INFORMATION

NOTES: A. The pulse generator has the following characteristics:  $Z_0 = 50 \Omega$ , duty cycle  $\leq 50\%$ . B. C<sub>L</sub> includes probe and jig capacitance.

### Figure 2. Driver Test Circuit and Waveforms for tPHL and tPLH Measurements (5-µs input)



NOTE A: The pulse generator has the following characteristics:  $Z_0 = 50 \Omega$ , duty cycle  $\leq 50\%$ .

Figure 3. Test Circuit and Waveforms for  $t_{THL}$  and  $t_{TLH}$  Measurements (20- $\!\mu s$  input)



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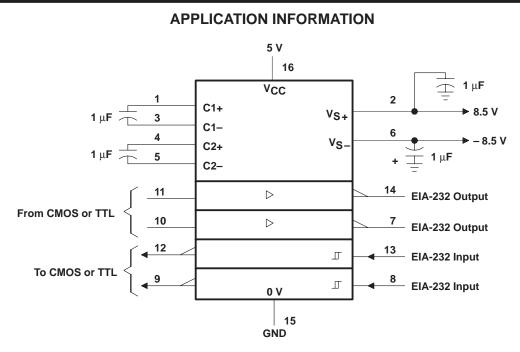


Figure 4. Typical Operating Circuit



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